

February 2007

# **FDMS2672**

# **N-Channel UltraFET Trench MOSFET**

**200V**, **20A**, **77m**Ω

## **Features**

- Max  $r_{DS(on)}$  = 77m $\Omega$  at  $V_{GS}$  = 10V,  $I_D$  = 3.7A
- Max  $r_{DS(on)}$  = 88m $\Omega$  at  $V_{GS}$  = 6V,  $I_D$  = 3.5A
- Low Miller Charge
- RoHS Compliant

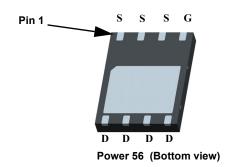


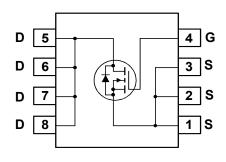
## **General Description**

UltraFET devices combine characteristics that enable benchmark efficiency in power conversion applications. Optimized for  $r_{DS(on)}$ , low ESR, low total and Miller gate charge, these devices are ideal for high frequency DC to DC converters.

## **Application**

■ DC - DC Conversion





# MOSFET Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
$V_{DS}$	Drain to Source Voltage			200	V
$V_{GS}$	Gate to Source Voltage	Gate to Source Voltage			V
	Drain Current -Continuous (Silicon limited)	T <sub>C</sub> = 25°C		20	
$I_D$	-Continuous	T <sub>A</sub> = 25°C	(Note 1a)	3.7	Α
	-Pulsed			20	
D	Power Dissipation	T <sub>C</sub> = 25°C		78	W
$P_{D}$	Power Dissipation $T_A = 25^{\circ}C$ (Note 1a)			2.5	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C

## **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	C/VV

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS2672	FDMS2672	Power 56	13"	12mm	3000 units

# **Electrical Characteristics** T<sub>J</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	200			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, referenced to 25°C		210		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 160V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V			±100	nA

### On Characteristics

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2	3.1	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, referenced to 25°C		-10		mV/°C
		$V_{GS} = 10V, I_D = 3.7A$		64	77	
r <sub>DS(on)</sub>	Drain to Source On Resistance	$V_{GS} = 6V, I_D = 3.5A$		69	88	mΩ
		$V_{GS} = 10V$ , $I_D = 3.7A T_J = 125°C$		129	156	
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10V, I_{D} = 3.7A$		14		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	\\ - 400\\ \\ - 0\\	1740	2315	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V, f = 1MHz	95	125	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1141112	30	45	pF
$R_g$	Gate Resistance	f = 1MHz	0.9		Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		22	34	ns
t <sub>r</sub>	Rise Time	$V_{DD} = 100V, I_{D} = 3.7A$ $V_{GS} = 10V, R_{GEN} = 6\Omega$	11	22	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> - 10V, R <sub>GEN</sub> - 012	36	57	ns
t <sub>f</sub>	Fall Time		10	20	ns
$Q_{g(TOT)}$	Total Gate Charge at 10V	$V_{GS} = 0V \text{ to } 10V$ $V_{DD} = 100V$	30	42	nC
$Q_{gs}$	Gate to Source Gate Charge	I <sub>D</sub> = 3.7A	7		nC
$Q_{gd}$	Gate to Drain "Miller" Charge		8		nC

## **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 3.7A (Note 2)	0.8	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	- I <sub>E</sub> = 3.7A, di/dt = 100A/μs	70	105	ns
Q <sub>rr</sub>	Reverse Recovery Charge	- I <sub>F</sub> = 3.7A, αι/αι = 100A/μS	238	357	nC

<sup>1</sup> R<sub>θ,JA</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>θ,JC</sub> is guaranteed by design while R<sub>θCA</sub> is determined by the user's board design.



a. 50°C/W when mounted on a 1 in² pad of 2 oz copper

b. 125°C/W when mounted on a minimum pad of 2 oz copper



2: Pulse Test: Pulse Width <  $300\mu$ s, Duty cycle < 2.0%.

## Typical Characteristics T<sub>.I</sub> = 25°C unless otherwise noted

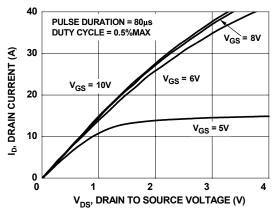


Figure 1. On Region Characteristics

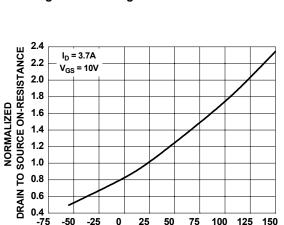


Figure 3. Normalized On Resistance vs Junction Temperature

T<sub>J</sub>, JUNCTION TEMPERATURE (°C)

-50 -25 0 25 50 75 100 125

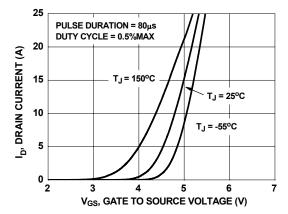


Figure 5. Transfer Characteristics

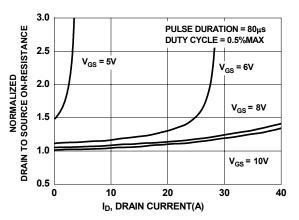


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

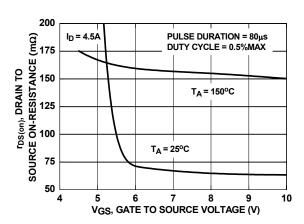


Figure 4. On-Resistance vs Gate to Source Voltage

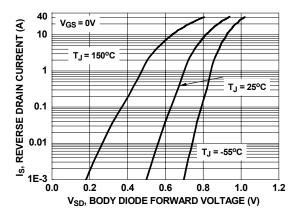


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# **Typical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

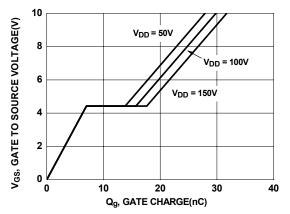


Figure 7. Gate Charge Characteristics

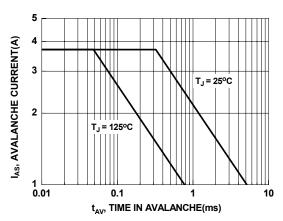


Figure 9. Unclamped Inductive Switching Capability

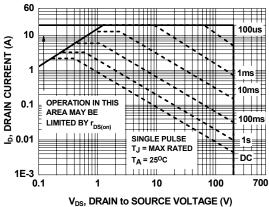


Figure 11. Forward Bias Safe
Operating Area

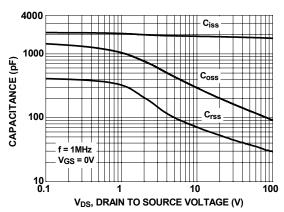


Figure 8. Capacitance vs Drain to Source Voltage

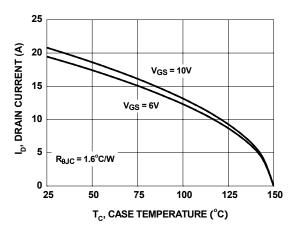


Figure 10. Maximum Continuous Drain Current vs Case Temperature

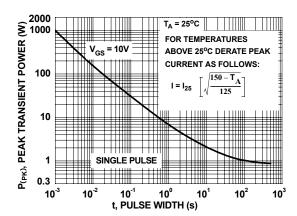


Figure 12. Single Pulse Maximum Power Dissipation

# Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

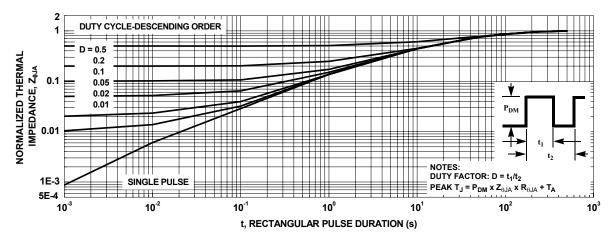
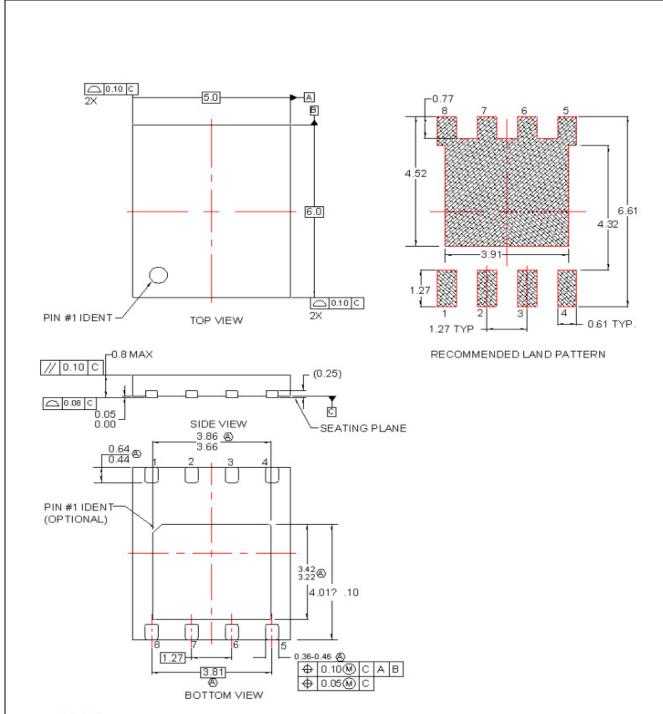


Figure 13. Transient Thermal Response Curve



## NOTES:

- A DOES NOT FULLY CONFORM TO JEDEC REGISTRATION, MO-229. DATED 11/2001.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- D. TERMINALS 5,6,7 AND 8 ARE TIED TO THE EXPOSED PADDLE

## MLP08GrevD

### TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

$ACEx^{TM}$	FACT Quiet Series™	$OCX^{TM}$	SILENT SWITCHER®	UniFET™
ActiveArray <sup>TM</sup>	GlobalOptoisolator <sup>TM</sup>	OCXPro™	SMART START <sup>TM</sup>	VCX <sup>TM</sup>
Bottomless <sup>TM</sup>	$GTO^{TM}$	OPTOLOGIC <sup>®</sup>	$SPM^{TM}$	Wire <sup>TM</sup>
Build it Now <sup>TM</sup>	HiSeCTM	OPTOPLANAR™	Stealth <sup>TM</sup>	
CoolFETTM	$I^2C^{TM}$	PACMANTM	SuperFETTM	
$CROSSVOLT^{TM}$	i-Lo™	POPTM	SuperSOTTM-3	
DOMETM	ImpliedDisconnect™	Power247 <sup>TM</sup>	SuperSOTTM-6	
EcoSPARK <sup>TM</sup>	IntelliMAXTM	PowerEdge <sup>TM</sup>	SuperSOTTM-8	
$E^2CMOS^{TM}$	ISOPLANAR <sup>TM</sup>	PowerSaver <sup>TM</sup>	SyncFETTM	
EnSigna <sup>TM</sup>	LittleFET <sup>TM</sup>	PowerTrench <sup>®</sup>	TCM <sup>TM</sup>	
$FACT^{\circledR}$	MICROCOUPLER <sup>TM</sup>	QFET <sup>®</sup>	TinyBoost™	
$FAST^{\circledR}$	MicroFET <sup>TM</sup>	$QS^{TM}$	TinyBuck <sup>TM</sup>	
FASTr <sup>TM</sup>	MicroPak <sup>TM</sup>	QT Optoelectronics <sup>TM</sup>	TinyPWM <sup>TM</sup>	
FPS™	MICROWIRE <sup>TM</sup>	Quiet Series <sup>TM</sup>	TinyPower <sup>TM</sup>	
FRFETTM	MSX™	RapidConfigure™	TinyLogic <sup>®</sup>	
	MSXPro™	RapidConnect™	$TINYOPTO^{TM}$	
Across the board. Around	the world.™	μSerDes™	TruTranslation™	
The Power Franchise®		ScalarPump™	UHC <sup>®</sup>	

### DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN, FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

### LIFE SUPPORT POLICY

Programmable Active Droop<sup>TM</sup>

ELIFE SOFT FOLICITY AND AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

### As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.

2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

## PRODUCT STATUS DEFINITIONS

### **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

Rev. I22